TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (U-MOSII)

# **TPC8303**

Lithium Ion Battery Applications Portable Equipment Applications Notebook PCs

• Low drain-source ON resistance :  $RDS(ON) = 27 \text{ m}\Omega \text{ (typ.)}$ 

• High forward transfer admittance :  $|Y_{fs}| = 7 S \text{ (typ.)}$ 

• Low leakage current  $:I_{DSS} = -10 \mu A \text{ (max) (V}_{DS} = -30 \text{ V)}$ 

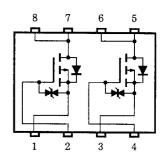
• Enhancement-mode :  $V_{th} = -0.8 \sim -2.0 \text{ V (V}_{DS} = -10 \text{ V, I}_{D} = -1 \text{ mA)}$ 

# **Maximum Ratings (Ta = 25°C)**

Char	acteristics	Symbol	Rating	Unit	
Drain-source vol	tage	$V_{DSS}$	-30	V	
Drain-gate voltag	ge (R <sub>GS</sub> = 20 kΩ)	$V_{DGR}$	-30	V	
Gate-source volt	age	$V_{GSS}$	±20	V	
Desir suggest	DC (Note 1)	I <sub>D</sub>	-4.5	Α	
Diaili Cuiteiil	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	A			
Drain power dissipation	operation	P <sub>D (1)</sub>	1.5	W	
(t = 10s)	at dual operation	P <sub>D(2)</sub>	1.0		
Drain power dissipation (t = 10s) (Note 2b)	operation	P <sub>D (1)</sub>	0.75	W	
	at dual operation	P <sub>D (2)</sub>	0.45	vv	
Single pulse ava		E <sub>AS</sub>	26	mJ	
Avalanche curre	nt	I <sub>AR</sub>	-4.5	Α	
Repetitive avalar Single-device va (Note		E <sub>AR</sub>	0.10	mJ	
Channel tempera	ature	T <sub>ch</sub>	150	°C	
Storage tempera	ture range	T <sub>stg</sub>	-55~150	°C	

Weight: 0.08 g (typ.)

## **Circuit Configuration**



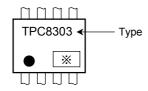
Note: For (Note 1), (Note 2a), (Note 2b), (Note 3a), (Note 3b), (Note 4) and (Note 5), please refer to the next page.

This transistor is an electrostatic sensitive device. Please handle with caution.

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit		
Thermal registance abannel to embient	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	83.3		
Thermal resistance, channel to ambient (t = 10s) (Note 2a)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	125	°C/W	
The word resistance about all to each in the	Single-device operation (Note 3a)	R <sub>th (ch-a) (1)</sub>	167	C/VV	
Thermal resistance, channel to ambient (t = 10s) (Note 2b)	Single-device value at dual operation (Note 3b)	R <sub>th (ch-a) (2)</sub>	278		

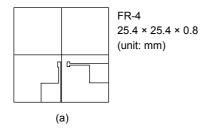
### Marking (Note 6)

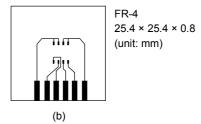


Note 1: Please use devices on condition that the channel temperature is below 150°C.

#### Note 2:

- a) Device mounted on a glass-epoxy board (a)
- b) Device mounted on a glass-epoxy board (b)





#### Note 3:

- a) The power dissipation and thermal resistance values are shown for a single device (During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device (During dual operation, power is evenly applied to both devices.)

Note 4: 
$$V_{DD}$$
 = -24 V,  $T_{ch}$  = 25°C (initial), L = 1.0 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = -4.5 A

Note 5: Repetitive rating: pulse width limited by maximum channel temperature

Note 6: ● on lower left of the marking indicates Pin 1.

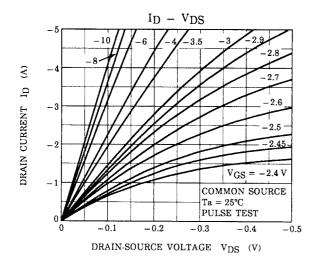
\* shows lot number. (year of manufacture: last decimal digit of the year of manufacture, month of manufacture: January to December are denoted by letters A to L respectively.)

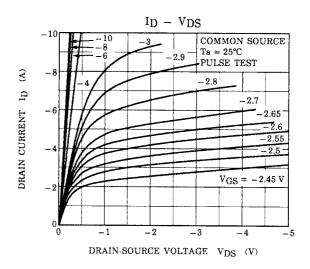
# **Electrical Characteristics (Ta = 25°C)**

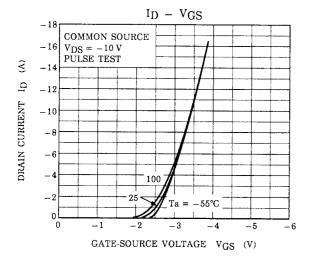
Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage cu	rrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μΑ	
Drain cut-off cur	Prain cut-off current		V <sub>DS</sub> = -30 V, V <sub>GS</sub> = 0 V		_	-10	μA	
Drain-source breakdown voltage		V <sub>(BR)DSS</sub>	$I_D = -10 \text{ mA}, V_{GS} = 0 \text{ V}$	-30 — —		V		
		V <sub>(BR)DSX</sub>	$I_D = -10 \text{ mA}, V_{GS} = 20 \text{ V}$	-15	1	1	V	
Gate threshold v	oltage	$V_{th}$	$V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA}$	-0.8		-2.0	V	
Drain-source O	N resistance	R <sub>DS (ON)</sub>	$V_{GS} = -4 \text{ V}, I_D = -2.2 \text{ A}$	_	55	65	mΩ	
Drain-source ON resistance		R <sub>DS (ON)</sub>	$V_{GS} = -10 \text{ V}, I_D = -2.2 \text{ A}$	_	27	35	11122	
Forward transfer admittance		Y <sub>fs</sub>	$V_{DS} = -10 \text{ V}, I_D = -2.2 \text{ A}$	3.5	7	_	S	
Input capacitance		C <sub>iss</sub>		_	970	_		
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	180	_	pF	
Output capacitance		Coss		_	370	_		
Switching time	Rise time	t <sub>r</sub>	$V_{GS}$ $\stackrel{0}{\underset{-10}{\text{V}}}$ $\stackrel{I_{D}=-2.2 \text{ A}}{\underset{-10}{\overset{\circ}{\underset{-10}{\text{VOUTE}}}}}$	_	17	_		
	Turn-ON time	t <sub>on</sub>	R <sub>L</sub> = 6.8 Ω		20		ns	
	Fall time	t <sub>f</sub>		l	75	ı	. 115	
	Turn-OFF time	t <sub>off</sub>	$V_{ m DD} \doteq -15   m V$ Duty $\leq 1\%$ , $t_{ m W} = 10  \mu  m s$		160			
Total gate charge (Gate-source plus gate-drain)		$Q_{g}$		_	28	_		
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \approx -24 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -4.5 \text{ A}$	_	16	_	nC	
Gate-drain ("miller") charge		$Q_{gd}$		_	12	_		

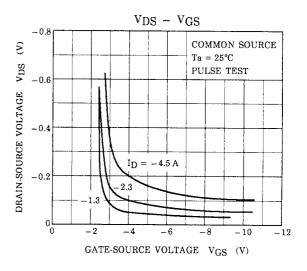
# **Source-Drain Ratings and Characteristics (Ta = 25°C)**

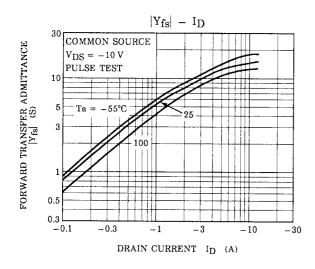
Charact	eristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I <sub>DRP</sub>	-	_	_	-18	А
Forward voltage (	oltage (diode) V <sub>DSF</sub> I <sub>DR</sub> = -4.5 A, V <sub>GS</sub> = 0 V		1	_	1.2	V	

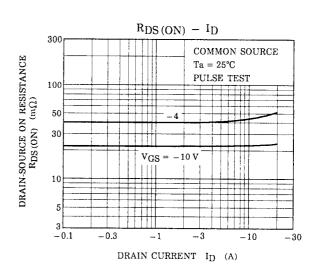




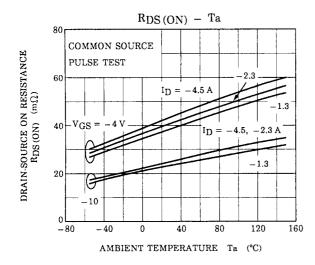


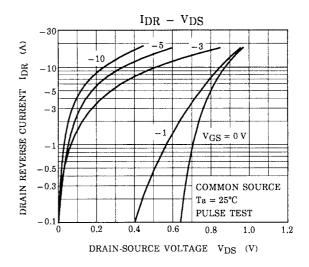


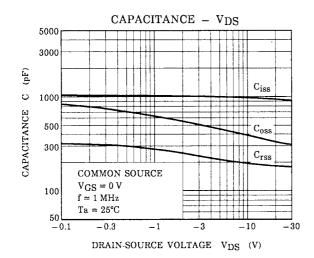


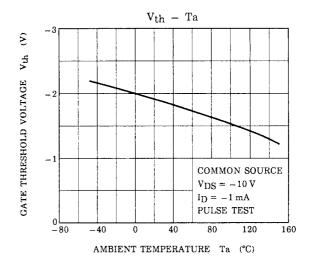


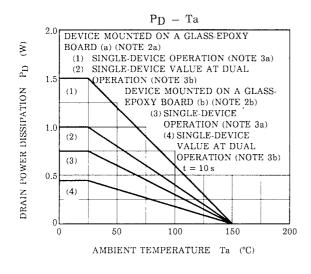
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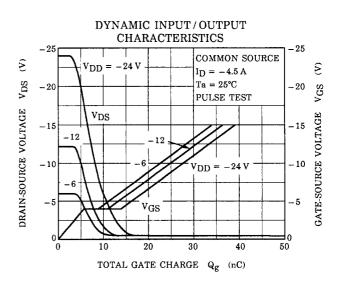




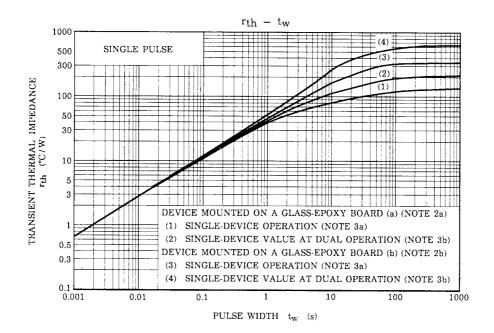


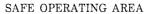


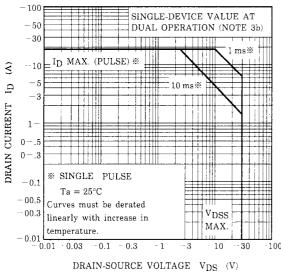


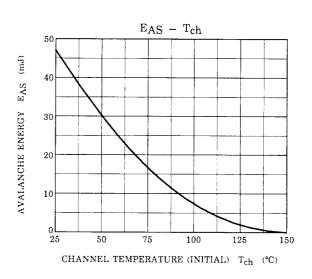


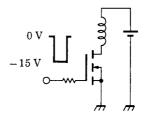
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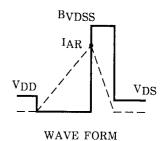








TEST CIRCUIT



 $T_{ch}=25^{\circ}C$  (Initial) Peak  $I_{AR}=-4.5\,A,~R_{G}=25\,\Omega$   $E_{AS}=\frac{1}{2}\cdot L\cdot I^{2}\cdot (~\frac{B_{VDSS}}{B_{VDSS}-V_{DD}})$   $V_{DD}=-24\,V,~L=1.0\,mH$ 

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